L Number	Hits	Search Text	DB	Time stamp
1	4572	(707/3 707/100 707/200).ccls.	USPAT	2004/06/07 13:30
2	12986	707/\$.ccls.	USPAT	2004/06/07 13:30
4	1	invalid adj1 guess\$9	USPAT	2004/06/07 13:31
3	2	database adj1 block adj1 address\$2	USPAT	2004/06/07 13:34
5 `.	74	guess\$9 same leaf	USPAT .	2004/06/07 13:35
6	0	(guess\$9 same leaf) and ((707/3 707/100	USPAT	2004/06/07 13:36
		707/200).ccls.)		
7	10443	guess\$9	USPAT	2004/06/07 13:36
8	34177	split\$3 and index	USPAT	2004/06/07 13:37
9	24	(split\$3 and index) and ((707/3 707/100	USPAT	2004/06/07 13:37
		707/200).ccls.) and guess\$9		,
10	24	((split\$3 and index) and ((707/3 707/100	USPAT	2004/06/07 13:41
		707/200).ccls.) and guess\$9) and (ratio		
		metadata address\$2 list block)		

IEEE HOME I SEARCH IEEE I SHOP I WEB ACCOUNT I CONTACT IEEE



Standards **Publications/Services** Welcome **United States Patent and Trademark Office** » Se. Quick Links FAQ Terms IEEE Peer Review Welcome to IEEE Xplore® Your search matched 0 of 1041798 documents. O- Home A maximum of 500 results are displayed, 15 to a page, sorted by Relevance - What Can **Descending** order. I Access? O- Log-out **Refine This Search:** You may refine your search by editing the current search expression or enteri **Tables of Contents** new one in the text box. — Journals Search: guess database block addresses & Magazines ☐ Check to search within this result set Conference **Proceedings Results Key:** O- Standards JNL = Journal or Magazine CNF = Conference STD = Standard Search O- By Author O- Basic **Results:** — Advanced No documents matched your query. Member Services - Join IEEE)- Establish IEEE Web Account O- Access the **IEEE Member**

Print Format

Digital Library

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |

New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online

Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Public	ations/Services Standards Conferences Careers/Jobs		
IEEE)	RELEASE 1.7		
Help FAQ Terms IEE	E Peer Review Quick Links Se.		
Welcome to IEEE Xplore® - Home - What Can I Access?	Your search matched 0 of 1041798 documents. A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order.		
○ - Log-out	Refine This Search:		
Tables of Contents	You may refine your search by editing the current search expression or enterinew one in the text box.		
O- Journals & Magazines	guess and database and splitting Search		
Conference Proceedings	Check to search within this result set Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard		
O- Standards			
Search			
O- By Author O- Basic O- Advanced	Results: No documents matched your query.		
Member Services - Join IEEE - Establish IEEE - Web Account			
O- Access the IEEE Member Digital Library			

Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved

IEEE HOME ! SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Standards

Publications/Services



Welcome **United States Patent and Trademark Office** » Se. **Quick Links** FAQ Terms IEEE Peer Review Welcome to IEEE Xplore® Your search matched 0 of 1041798 documents. O- Home A maximum of 500 results are displayed, 15 to a page, sorted by Relevance - What Can **Descending** order. I Access? O- Log-out **Refine This Search:** You may refine your search by editing the current search expression or enterior **Tables of Contents** new one in the text box. Journals database and block and address and split and primary Search & Magazines ☐ Check to search within this result set - Conference **Proceedings Results Key:** O- Standards JNL = Journal or Magazine CNF = Conference STD = Standard Search O- By Author O- Basic Results: C - Advanced No documents matched your query. **Member Services** O Join IEEE O- Establish IEEE Web Account O- Access the **IEEE Member** Digital Library

Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Publications/Services Standards Conferences Welcome **United States Patent and Trademark Office** » Se. **Quick Links** FAQ Terms IEEE Peer Review Welcome to IEEE Xplore® Your search matched **0** of **1041798** documents. O- Home A maximum of 500 results are displayed, 15 to a page, sorted by Relevance - What Can Descending order. I Access? O- Log-out **Refine This Search:** You may refine your search by editing the current search expression or enteri **Tables of Contents** new one in the text box. Journals database and block and index and leaf Search & Magazines ☐ Check to search within this result set Conference **Proceedings Results Key:** O- Standards JNL = Journal or Magazine CNF = Conference STD = Standard Search C By Author O- Basic Results: Advanced No documents matched your query. **Member Services**)- Join IEEE Establish IEEE Web Account

Print Format

O- Access the IEEE Member Digital Library

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Publications/Services Standards Conferences Welcome -**United States Patent and Trademark Office** Quick Links ∇ FAQ Terms IEEE Peer Review Welcome to IEEE Xplore® Your search matched **0** of **1041798** documents. O- Home A maximum of 500 results are displayed, 15 to a page, sorted by Relevance — What Can Descending order. I Access? O- Log-out **Refine This Search:** You may refine your search by editing the current search expression or enteri Tables of Contents new one in the text box. — Journals database and new and leaf and dba Search & Magazines ☐ Check to search within this result set Conference **Proceedings Results Key:** O- Standards JNL = Journal or Magazine CNF = Conference STD = Standard Search O- By Author O- Basic Results: Advanced No documents matched your query. **Member Services** Join IEEE - Establish IEEE Web Account C - Access the **IEEE Member**

Print Format

Digital Library

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help. | FAQ | Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved